

Functional description

The AS7C31024B is a high performance CMOS 1,048,576-bit Static Random Access Memory (SRAM) device organized as 131,072 words x 8 bits. It is designed for memory applications where fast data access, low power, and simple interfacing are desired.

Equal address access and cycle times $(t_{AA},\,t_{RC},\,t_{WC})$ of 10/12/15/20 ns with output enable access times (t_{OE}) of 5, 6, 7, 8 ns are ideal for high performance applications. Active high and low chip enables ($\overline{\text{CE1}}$, CE2) permit easy memory expansion with multiple-bank systems.

When $\overline{\text{CE1}}$ is high or CE2 is low, the device enters standby mode. If inputs are still toggling, the device will consume I_{SB} power. If the bus is static, then full standby power is reached (I_{SR1}). For example, the AS7C31024B is guaranteed not to exceed 18 mW under nominal full standby conditions.

A write cycle is accomplished by asserting write enable (\overline{WE}) and both chip enables ($\overline{CE1}$, CE2). Data on the input pins I/O0 through I/O7 is written on the rising edge of WE (write cycle 1) or the active-to-inactive edge of CEI or CE2 (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable (\overline{OE}) or write enable (\overline{WE}) .

A read cycle is accomplished by asserting output enable (\overline{OE}) and both chip enables $(\overline{CEI}, CE2)$, with write enable (\overline{WE}) high. The chip drives I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive, or write enable is active, output drivers stay in high-impedance mode.

Absolute maximum ratings

Parameter	Symbol	Min	Max	Unit
Voltage on V _{CC} relative to GND	V _{t1}	-0.50	+5.0	V
Voltage on any pin relative to GND	V _{t2}	-0.50	V _{CC} +0.50	V
Power dissipation	P_{D}	_	1.0	W
Storage temperature (plastic)	T _{stg}	-65	+150	°C
Ambient temperature with V _{CC} applied	T _{bias}	-55	+125	°C
DC current into outputs (low)	I _{OUT}	_	20	mA

Note: Stresses greater than those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Truth table

CE1	CE2	WE	OE	Data	Mode
Н	X	X	X	High Z	Standby (I _{SB} , I _{SB1})
X	L	X	X	High Z	Standby (I _{SB} , I _{SB1})
L	Н	Н	Н	High Z	Output disable (I _{CC})
L	Н	Н	L	D _{OUT}	Read (I _{CC})
L	Н	L	X	D_{IN}	Write (_{ICC})

Key: X = don't care, L = low, H = high



Recommended operating conditions

Parameter	Symbol	Min	Nominal	Max	Unit	
Supply voltage		V _{CC}	3.0	3.3	3.6	V
Input voltage		V _{IH}	2.0	_	$V_{CC} + 0.5$	V
		V _{IL}	-0.5	_	0.8	V
Ambient operating temperature	commercial	T_A	0	_	70	°C

DC operating characteristics (over the operating range) 1

			-1	10	-1	12	-1	15	-20		Unit
Parameter	Sym	Test conditions		Max	Min	Max	Min	Max	Min	Max	Omt
Input leakage current	$ I_{LI} $	$V_{CC} = Max$, $V_{IN} = GND$ to V_{CC}		1	-	1	-	1	-	1	μΑ
Output leakage current	$ I_{LO} $	$V_{CC} = Max$, $\overline{CE1} = V_{IH}$ or $CE2 = V_{IL}$, $V_{OUT} = GND$ to V_{CC}		1	П	1	ı	1	П	1	μΑ
Operating power supply current	I_{CC}	$V_{CC} = Max, \overline{CE1} \le V_{IL},$ $CE2 \ge V_{IH}, f = f_{Max},$ $I_{OUT} = 0 \text{ mA}$	I	70	I	65	I	60	I	55	mA
	I_{SB}	$V_{CC} = Max$, $\overline{CE1} \ge V_{IH}$ and/or $CE2 \le V_{IL}$, $f = f_{Max}$	ı	30	ı	25	ı	20	ı	20	
Standby power supply current	I_{SB1}	$\begin{split} V_{CC} = \text{Max, } \overline{CE1} &\geq V_{CC} - 0.2 \text{V and/} \\ & \text{or } CE2 \leq 0.2 \text{V} \\ & V_{IN} \leq 0.2 \text{V or} \\ & V_{IN} \geq V_{CC} - 0.2 \text{V, } f = 0 \end{split}$	-	5	-	5	-	5	-	5	mA
Output voltage	V _{OL}	$I_{OL} = 8 \text{ mA}, V_{CC} = \text{Min}$	_	0.4	-	0.4	_	0.4	-	0.4	V
- supur .orage	V _{OH}	$I_{OH} = -4 \text{ mA}, V_{CC} = \text{Min}$	2.4	_	2.4	_	2.4	_	2.4	_	V

Capacitance (f = 1 MHz, $T_a = 25$ °C, $V_{CC} = NOMINAL$)²

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C _{IN}	$A, \overline{CE1}, CE2, \overline{WE}, \overline{OE}$	$V_{IN} = 0V$	5	pF
I/O capacitance	C _{I/O}	I/O	$V_{IN} = V_{OUT} = 0V$	7	pF

 V_{IL} = -1.0V for pulse width less than 5ns V_{IH} = V_{CC} + 1.5V for pulse width less than 5ns



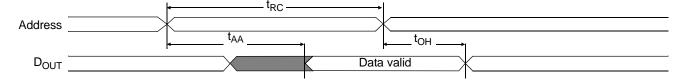
Read cycle (over the operating range)^{3,9,12}

		-1	10	-1	2	-1	15	-2	20		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	10	-	12	_	15	_	20		ns	
Address access time	t _{AA}	_	10	_	12	_	15	-	20	ns	3
Chip enable (CE1) access time	t _{ACE1}	_	10	_	12	_	15	-	20	ns	3, 12
Chip enable (CE2) access time	t _{ACE2}	_	10	_	12	_	15	-	20	ns	3, 12
Output enable (OE) access time	t _{OE}	_	5	_	6	_	7	_	8	ns	
Output hold from address change	t _{OH}	3	_	3	_	3	_	3	-	ns	5
CE1 low to output in low Z	t _{CLZ1}	3	-	3	-	3	_	3	_	ns	4, 5, 12
CE2 high to output in low Z	t _{CLZ2}	3	_	3	_	3	_	3	-	ns	4, 5, 12
CE1 high to output in high Z	t _{CHZ1}	_	3	_	3	_	4	-	5	ns	4, 5, 12
CE2 low to output in high Z	t _{CHZ2}	_	3	_	3	_	4	_	5	ns	4, 5, 12
OE low to output in low Z	t _{OLZ}	0	_	0	_	0	_	0	_	ns	4, 5
OE high to output in high Z	t _{OHZ}	_	5	_	6	_	7	_	8	ns	4, 5
Power up time	t _{PU}	0	-	0	_	0	_	0	_	ns	4, 5, 12
Power down time	t _{PD}	_	10	_	12	_	15	_	20	ns	4, 5, 12

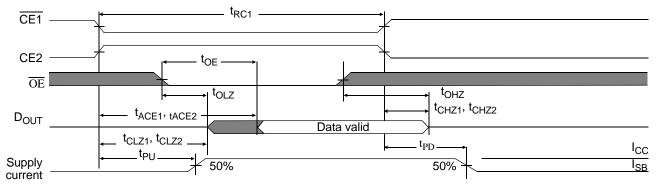
Key to switching waveforms



Read waveform 1 (address controlled)^{3,6,7,9,12}



Read waveform 2 (CE1, CE2, and OE controlled)^{3,6,8,9,12}

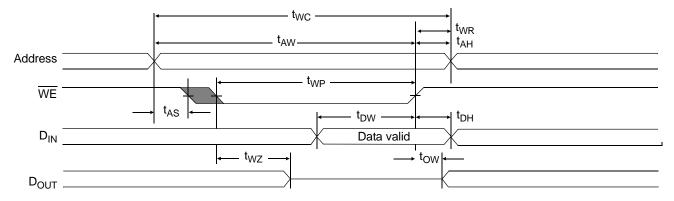




Write cycle (over the operating range)^{11, 12}

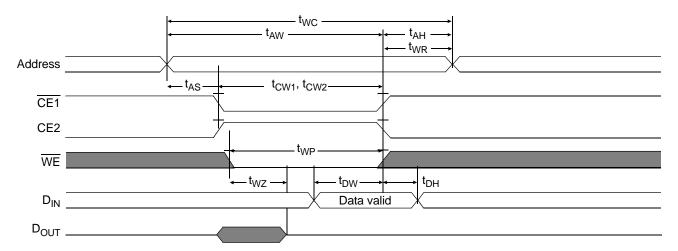
		-10		-1	12	-15		-20			
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Write cycle time	t_{WC}	10	_	12	_	15	_	20	_	ns	
Chip enable (CE1) to write end	t _{CW1}	8	_	9	_	10	_	12	_	ns	12
Chip enable (CE2) to write end	t _{CW2}	8	_	9	_	10	_	12	_	ns	12
Address setup to write end	t _{AW}	8	_	9	_	10	_	12	_	ns	
Address setup time	t _{AS}	0	_	0	_	0	_	0	_	ns	12
Write pulse width	t_{WP}	7	_	8	_	9	_	12	_	ns	
Write recovery time	t_{WR}	0	_	0	_	0	_	0	_	ns	
Address hold from end of write	t _{AH}	0	_	0	_	0	_	0	_	ns	
Data valid to write end	t_{DW}	5	_	6	_	8	_	10	_	ns	
Data hold time	t _{DH}	0	_	0	_	0	_	0	_	ns	4, 5
Write enable to output in high Z	t_{WZ}	_	5	-	6	_	7	_	8	ns	4, 5
Output active from write end	t _{OW}	1	_	1	_	1	_	1	_	ns	4, 5

Write waveform 1 ($\overline{\text{WE}}$ controlled) I0,II,I2





Write waveform 2 (CE1 and CE2 controlled)^{10,11,12}



AC test conditions

- Output load: see Figure B.
- Input pulse level: GND to 3.0V. See Figure A.
- Input rise and fall times: 2 ns. See Figure A.
- Input and output timing reference levels: 1.5V.



Thevenin equivalent:

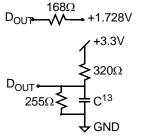


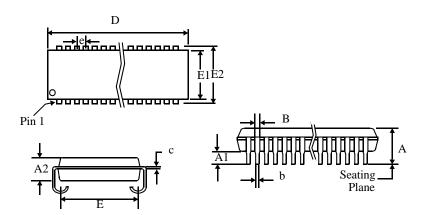
Figure B: 3.3V Output load

Notes

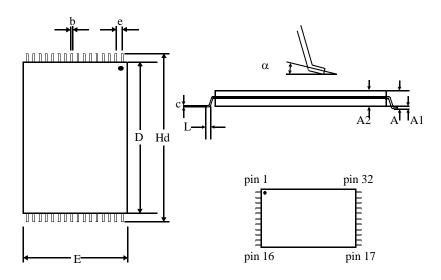
- 1 During V_{CC} power-up, a pull-up resistor to V_{CC} on $\overline{CE1}$ is required to meet I_{SB} specification.
- 2 This parameter is sampled and not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A, and B.
- $4 t_{CLZ}$ and t_{CHZ} are specified with CL = 5pF, as in Figure C. Transition is measured ± 500 mV from steady-state voltage.
- 5 This parameter is guaranteed, but not 100% tested.
- 6 WE is high for read cycle.
- $\overline{\text{CE1}}$ and $\overline{\text{OE}}$ are low and CE2 is high for read cycle.
- 8 Address valid prior to or coincident with CE1 transition Low.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 N/A
- 11 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 12 <u>CE1</u> and CE2 have identical timing.
- 13 C = 30 pF, except all high Z and low Z parameters where C = 5 pF.
- 14 N/A



Package dimensions



	32-pin S m		32-pin SOJ 400 mil				
	Min	Min Max		Max			
A	0.128	0.145	0.132	0.146			
A1	0.025	-	0.025	-			
A2	0.095	0.105	0.105	0.115			
В	0.026	0.032	0.026	0.032			
b	0.016	0.020	0.015	0.020			
С	0.007	0.010	0.007	0.013			
D	0.820	0.830	0.820	0.830			
Е	0.255	0.275	0.354	0.378			
E1	0.295	0.305	0.395	0.405			
E2	0.330	0.340	0.435	0.445			
e	0.050	BSC	0.050	BSC			



	32-pin TSOP 8×20 mm									
	Min	Max								
A	_	1.20								
A1	0.05	0.15								
A2	0.95	1.05								
b	0.17	0.27								
С	0.10	0.21								
D	18.30	18.50								
e	0.50 ne	ominal								
Е	7.90	8.10								
Hd	19.80	20.20								
L	0.50	0.70								
α	0°	5°								



Ordering codes

Package \ Access time	Temp	10 ns	12 ns	15 ns	20 ns
Plastic SOJ, 300 mil	Commercial	AS7C31024B-10TJC	AS7C31024B-12TJC	AS7C31024B-15TJC	AS7C31024B-20TJC
Plastic SOJ, 400 mil	Commercial	AS7C31024B-10JC	AS7C31024B-12JC	AS7C31024B-15JC	AS7C31024B-20JC
TSOP1 8×20 mm	Commercial	AS7C31024B-10TC	AS7C31024B-12TC	AS7C31024B-15TC	AS7C31024B-20TC
sTSOP1 8 x 13.4mm	Commercial	AS7C31024B-10STC	AS7C31024B-12STC	AS7C31024B-15STC	AS7C31024B-20STC

Add suffix 'N' to the above part number for lead free parts (Ex. AS7C31024B-10TJCN)

Part numbering system

AS7C	X	1024B	-XX	X	X	X
SRAM prefix	3 = 3.3 V CMOS	Device number	Access time	Package: T = TSOP1 8×20 mm ST = sTSOP1 8 x 13.4 mm J = SOJ 400 mil TJ = SOJ 300 mil	Temperature range C = Commercial, 0° C to 70° C	N=Lead Free Part





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